

Understanding and Comparisons of High Speed ADC and DAC Architectures

TIPL 4706

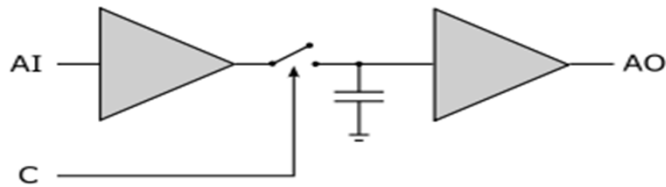
Presented by Richard Prentice

Prepared by Richard Prentice

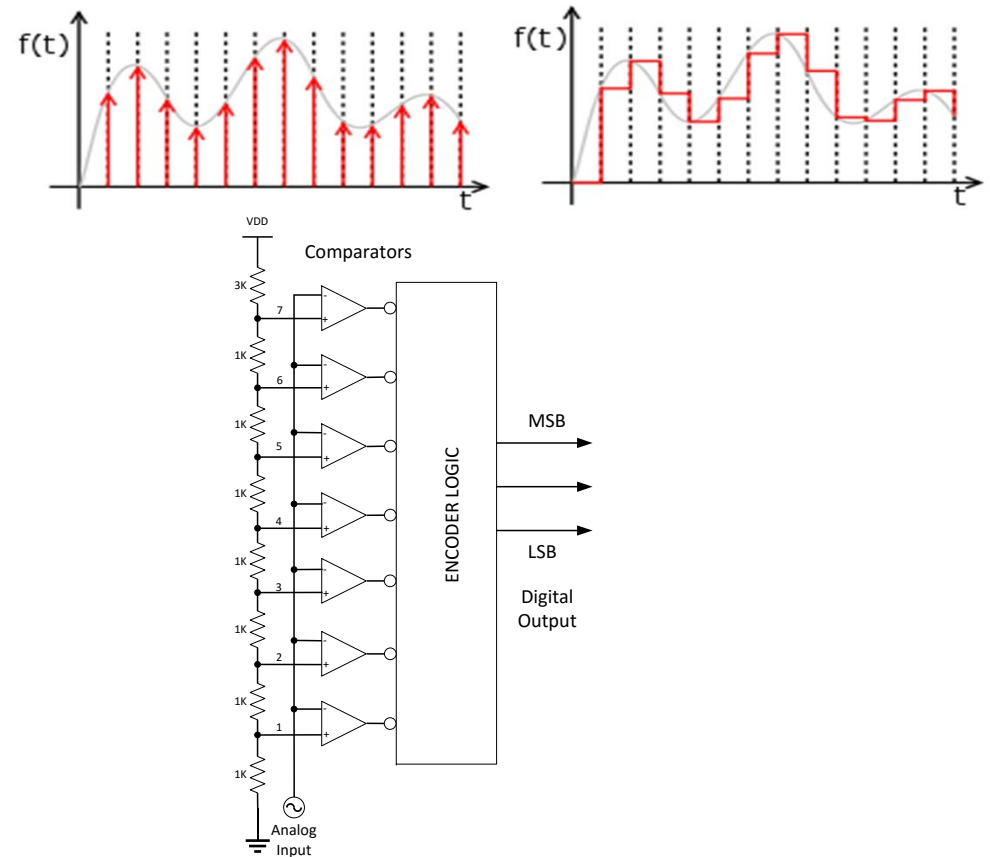


Architectures

- Flash converter
 - Track and hold

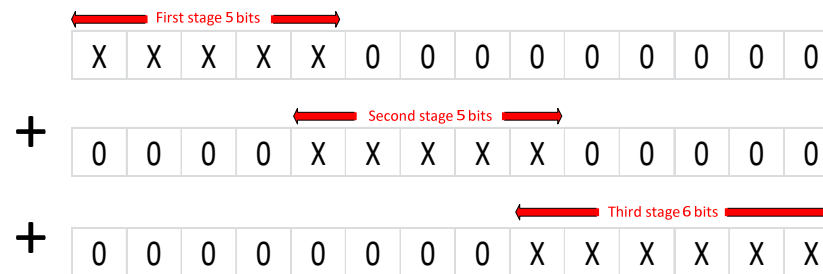
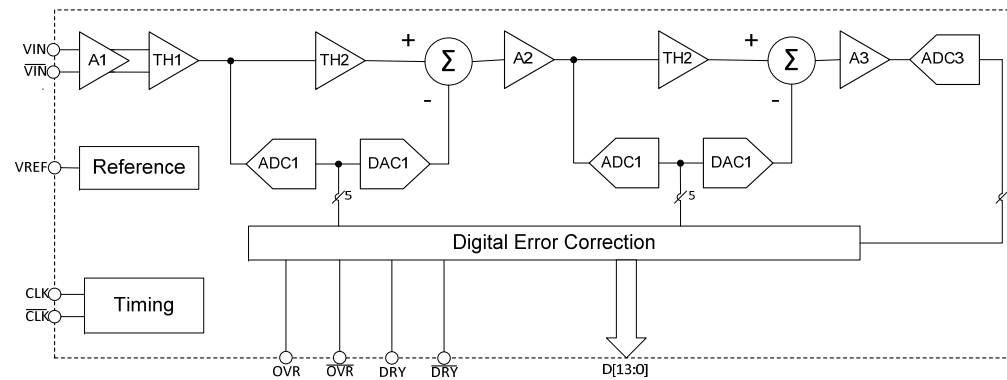


- Comparators
 - For n bits:
 - $2^n - 1$ comparators



Architectures

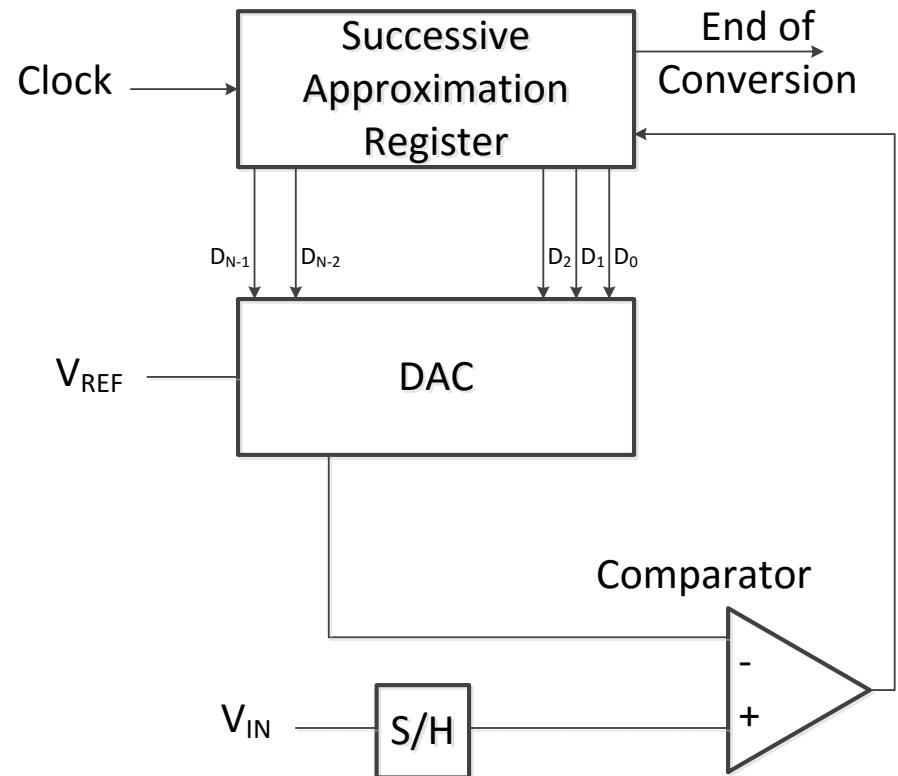
- Pipelined – successive stages of flash
 - Each stage adds n bits more precision
 - Requires good matching/trimming



Result = (First stage bits * 512) + (Second stage bits * 32) + Third stage bits

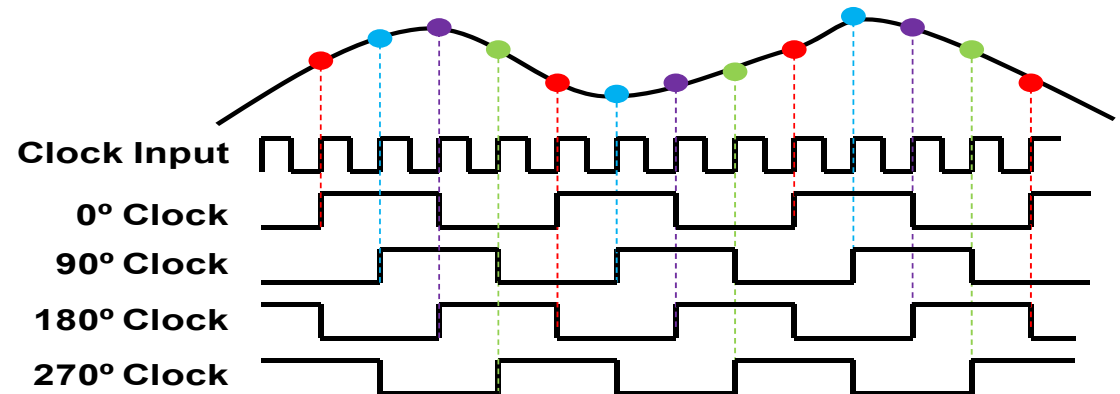
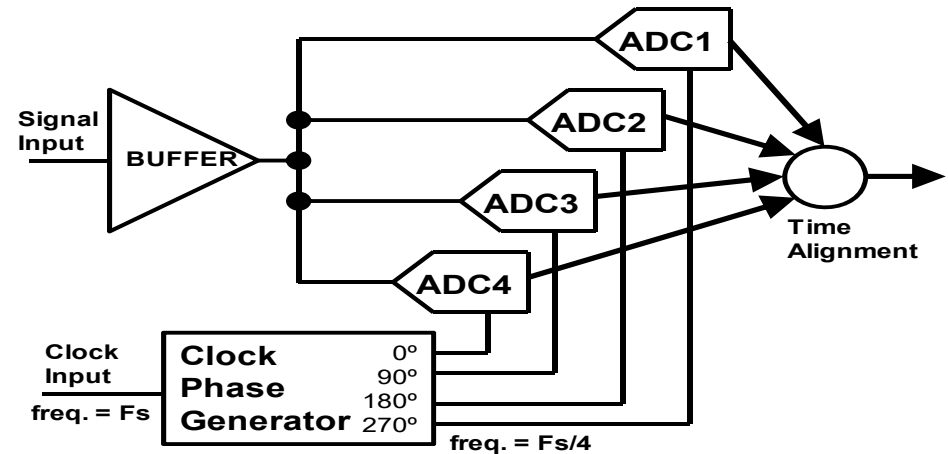
Architectures

- SAR – Successive Approximation
 - DAC = digital-to-analog converter
 - EOC = end of conversion
 - SAR = successive approximation register
 - S/H = sample and hold circuit
 - V_{in} = input voltage
 - V_{ref} = reference voltage
 - Source - Wikipedia



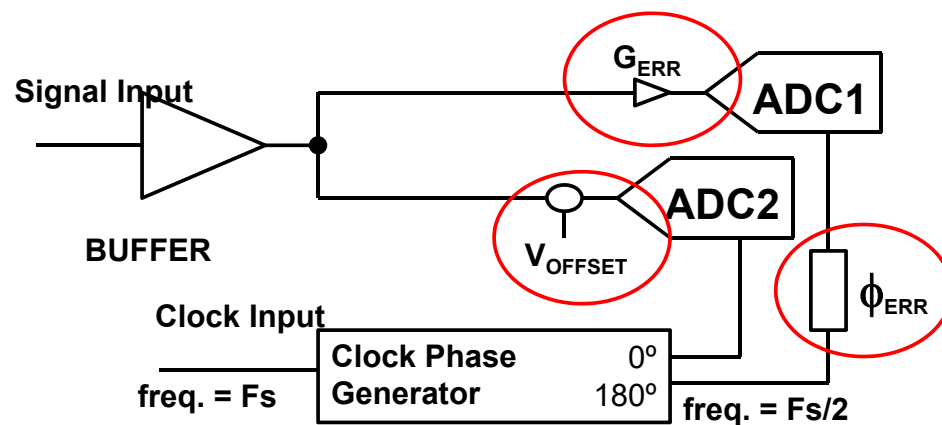
ADC Interleaving Basics

- Multiple ADC cores sample signal to increase total sampling rate
- ADC cores sample at same divided frequency but different phase offset
- Digital outputs are re-aligned in time
- Input buffer typically drives cores



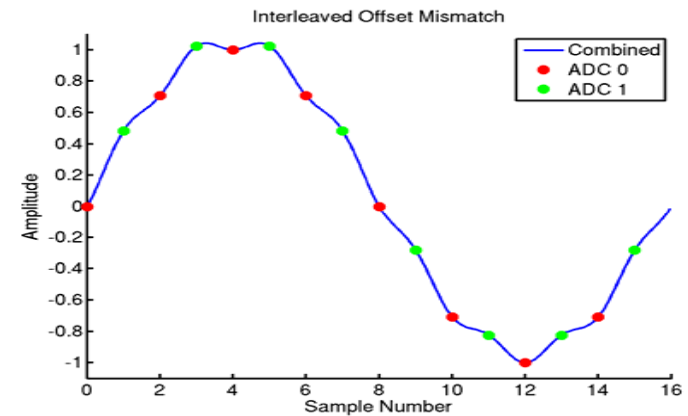
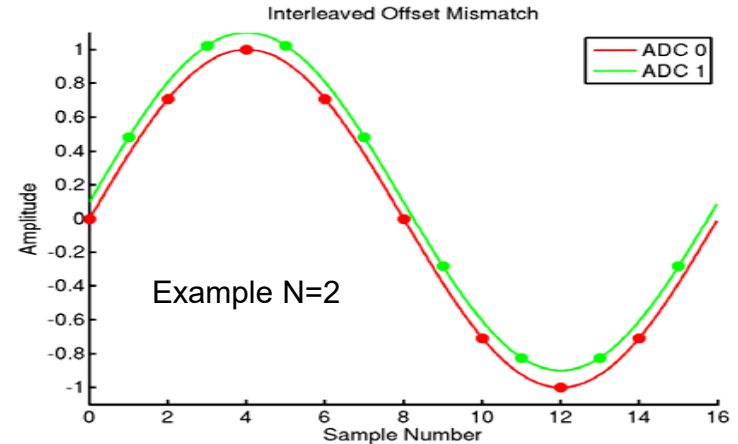
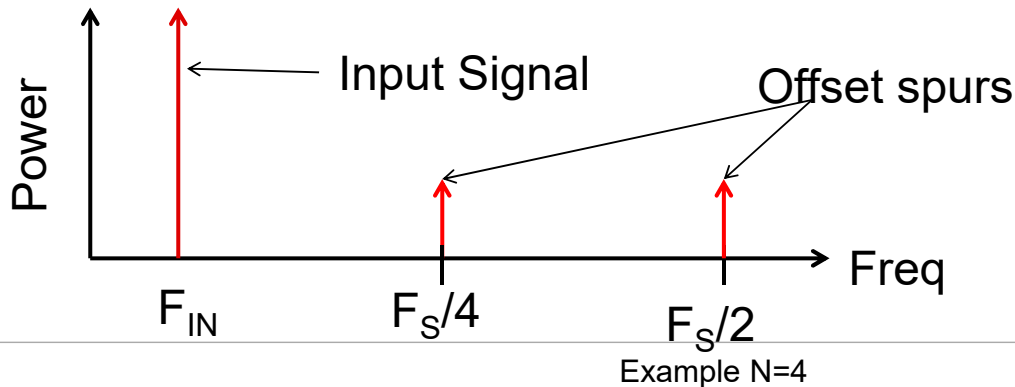
Non-Ideal Interleaving

- Offset Errors
 - Mismatched ADC core voltage offset
- Amplitude Errors
 - ADC core gain error
 - ADC reference voltage error
- Phase Errors
 - Input routing delay
 - Input BW difference
 - Clock phase error
 - ADC sampling instant



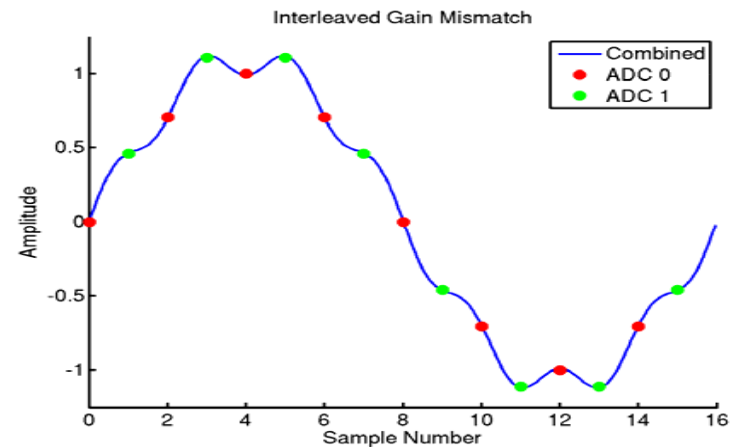
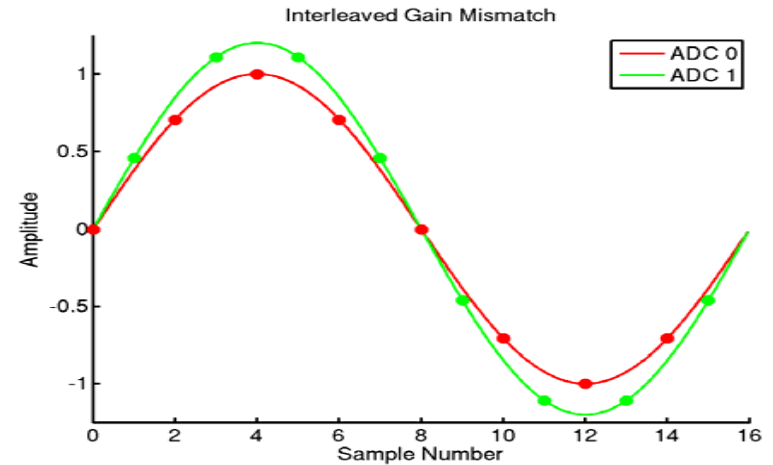
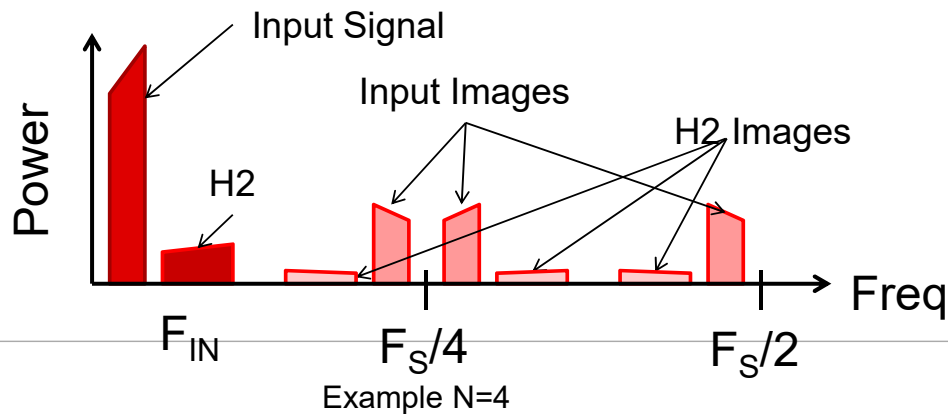
Non-Ideal Interleaving

- Offset Error
 - Different voltage offset at ADC input between different cores
- Alternating up/down in transient waveform
- Creates signal independent spurs in spectrum at $F_s \cdot n/N$ for $n=1, 2, \dots, N-1$ where N is # of interleaved cores



Non-Ideal Interleaving

- Amplitude (Gain) errors
 - Gain difference between different ADC cores
- Creates $N-1$ input signal dependent images from 0 to $F_s/2$ in a repetitive, mirror-image pattern where N is # of interleaved cores
- Also creates harmonic distortion images



Interleaving Correction

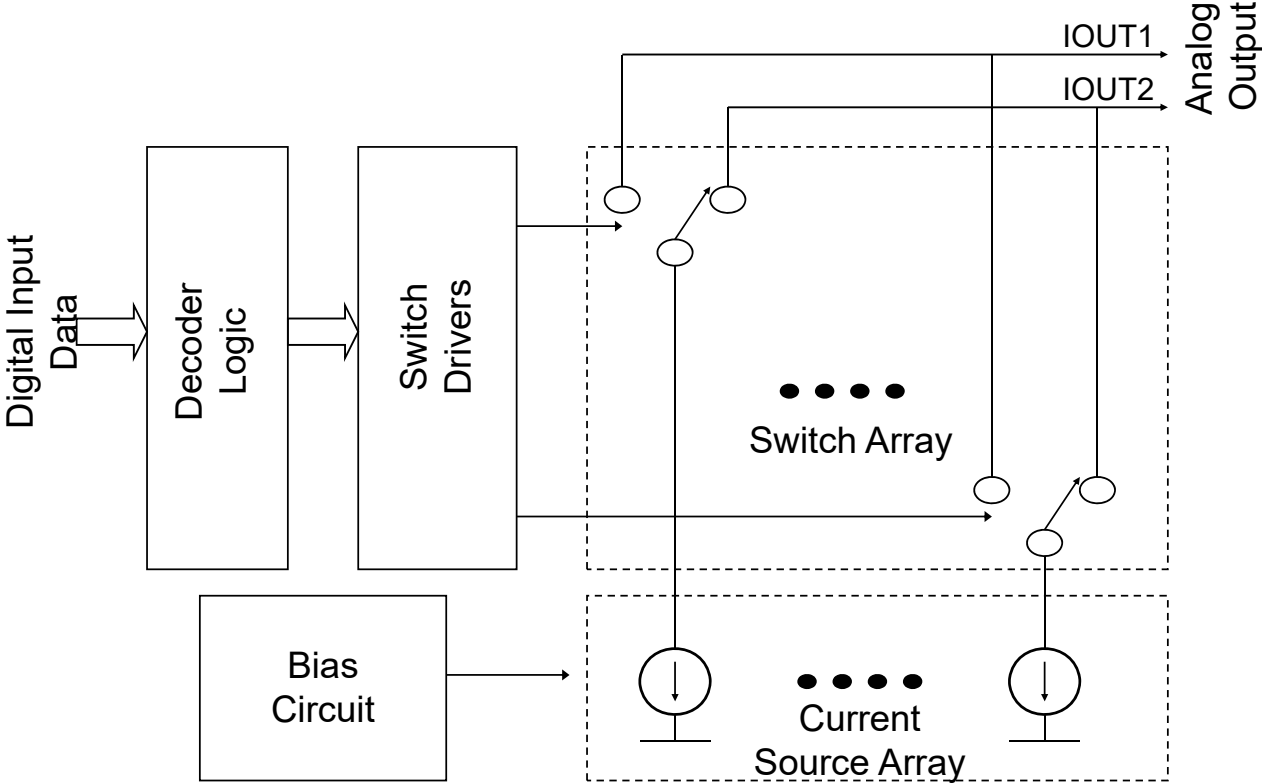
- Relying on process matching not suitable for most applications
- Interleave correction reduces spectrum offset spurs and images
- *Estimate* the errors and *correct* the data with coefficients
- Estimation
 - Detection in time-domain or frequency domain
 - Convergence
- Correction
 - Analog/Digital
- Calibration time
 - Foreground: Calibration interrupts normal operation
 - Background: Calibration runs continuously

Current Steering DAC



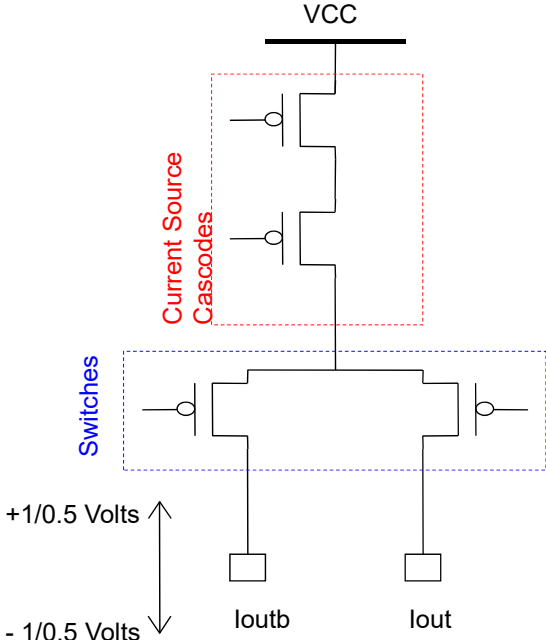
Full Scale = 30mA

IOUT1	IOUT2
30mA	0mA
15mA	15mA
0mA	30mA



DACs can be current source or current sink

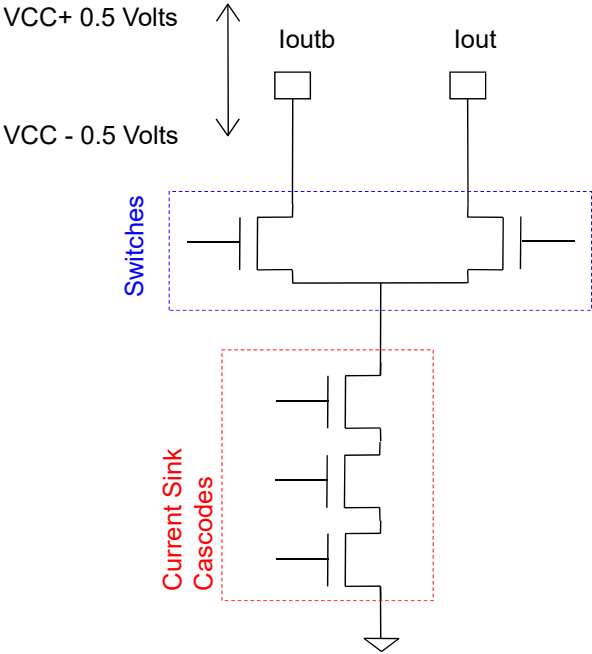
PMOS



DAC90x, DAC290x, DAC2932,
DAC56x2

DAC34xx, DAC3174

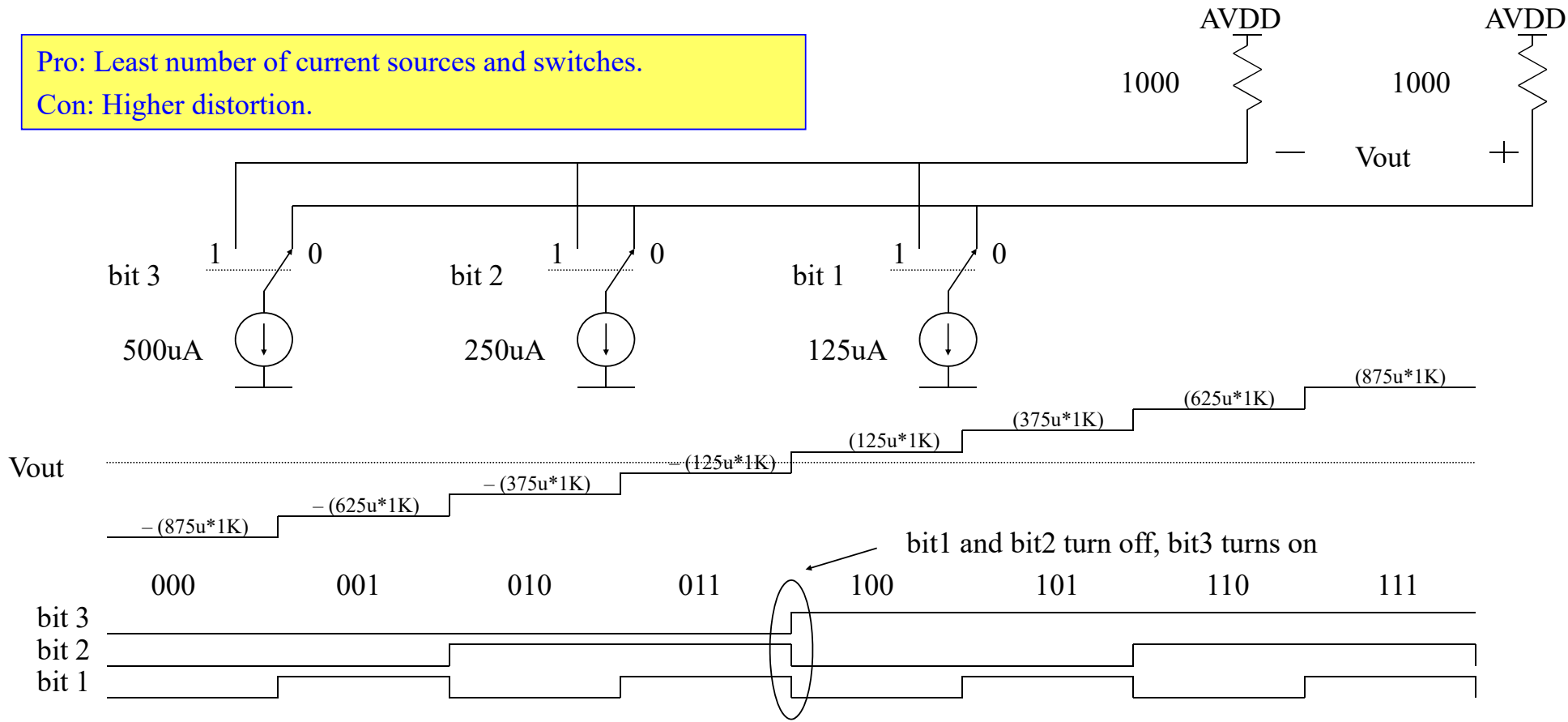
NMOS



DAC5686/87/88/89,
DAC5681/82Z,
DAC3282/83
DAC3152/62

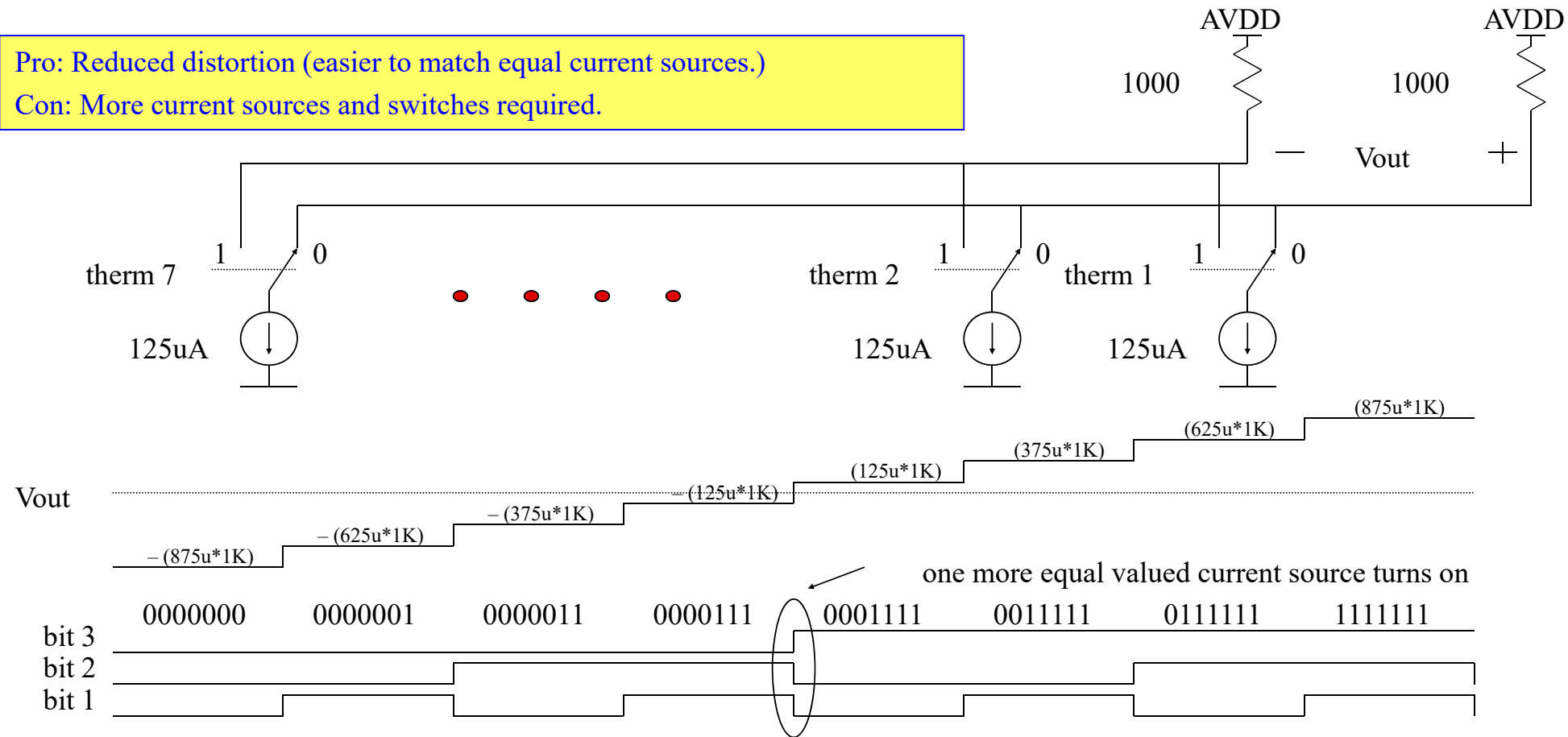
Simple 3-bit Binary DAC

Pro: Least number of current sources and switches.
 Con: Higher distortion.

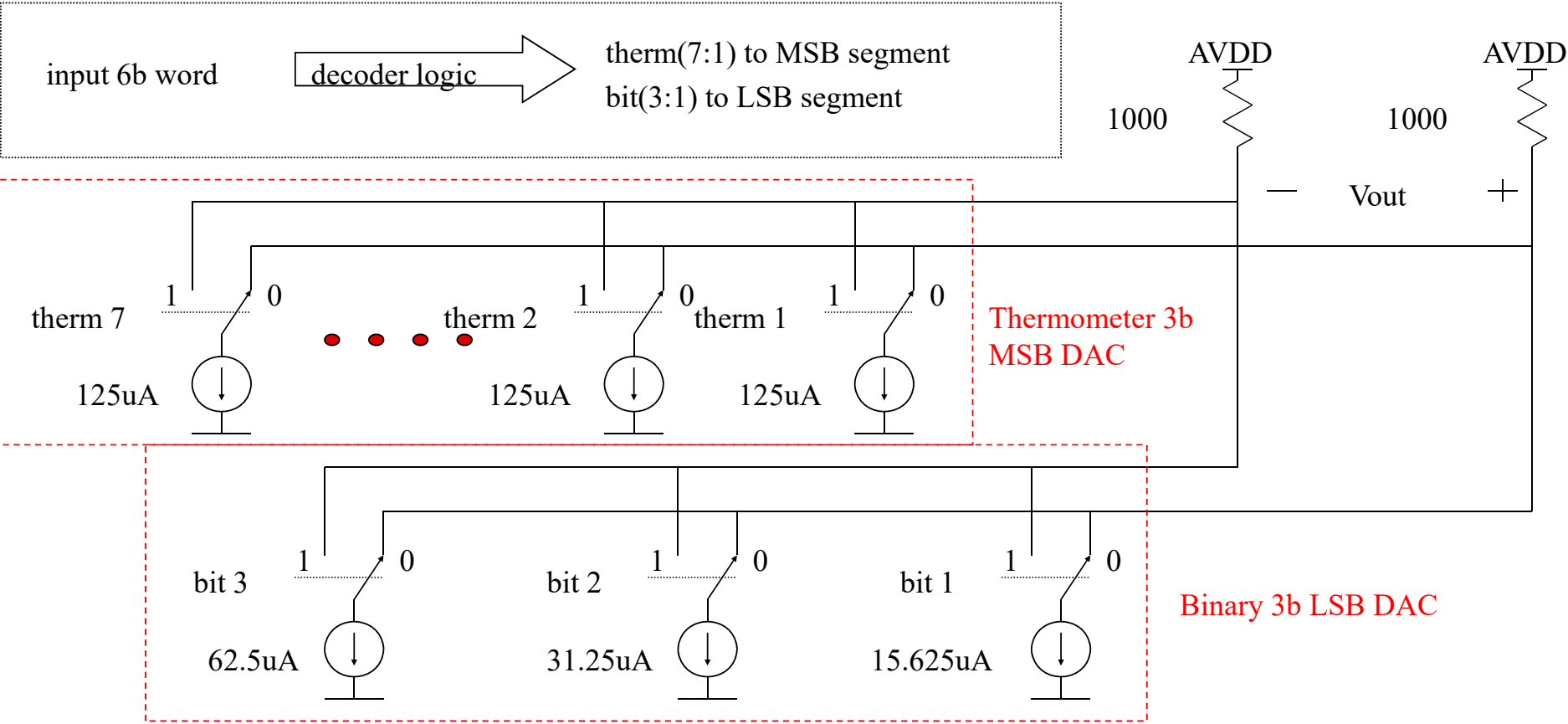


Equivalent 3-bit Thermometer Coded DAC

Pro: Reduced distortion (easier to match equal current sources.)
 Con: More current sources and switches required.

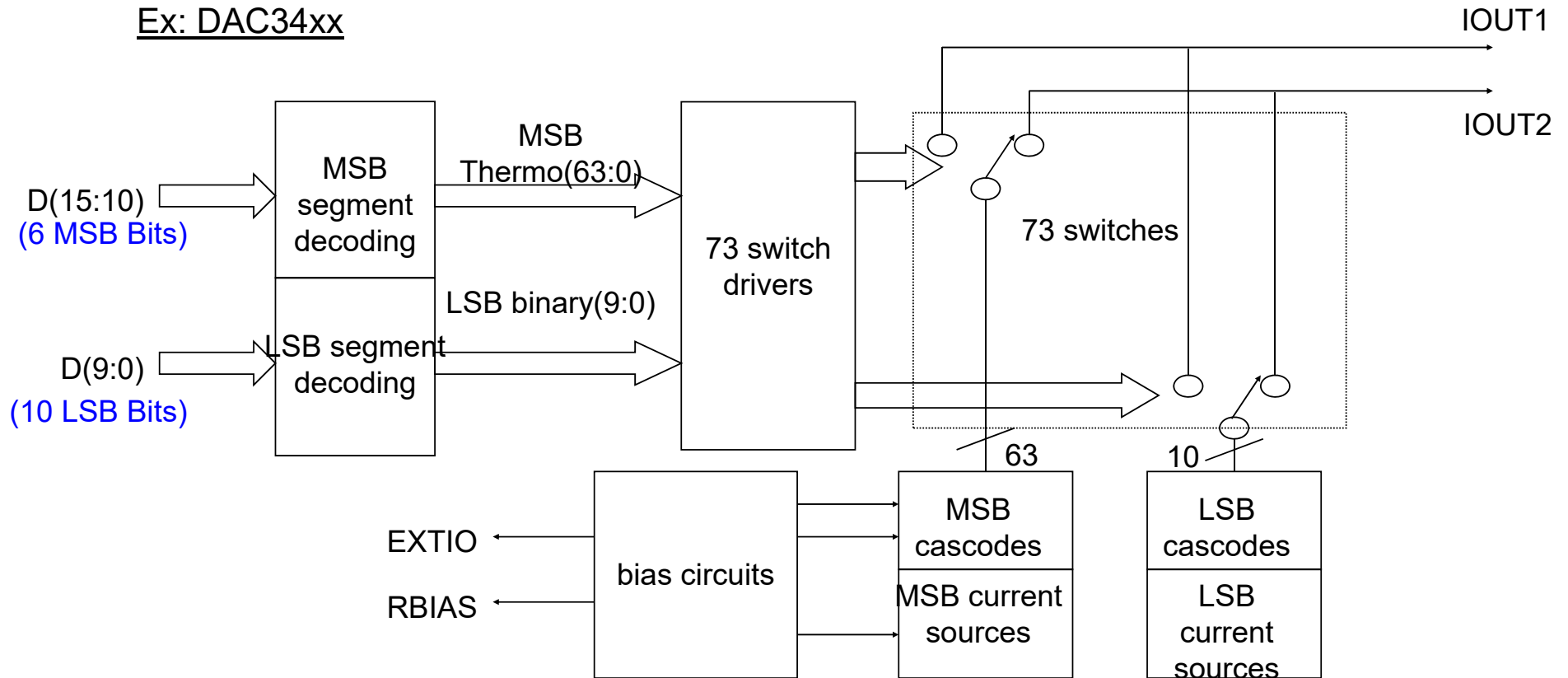


DACs can be segmented and mixed coded



Simplified TI 16b DAC topology

Ex: DAC34xx



Thanks for your time!



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